

HabEx Coronagraph Masks in Polarization Ray-tracing

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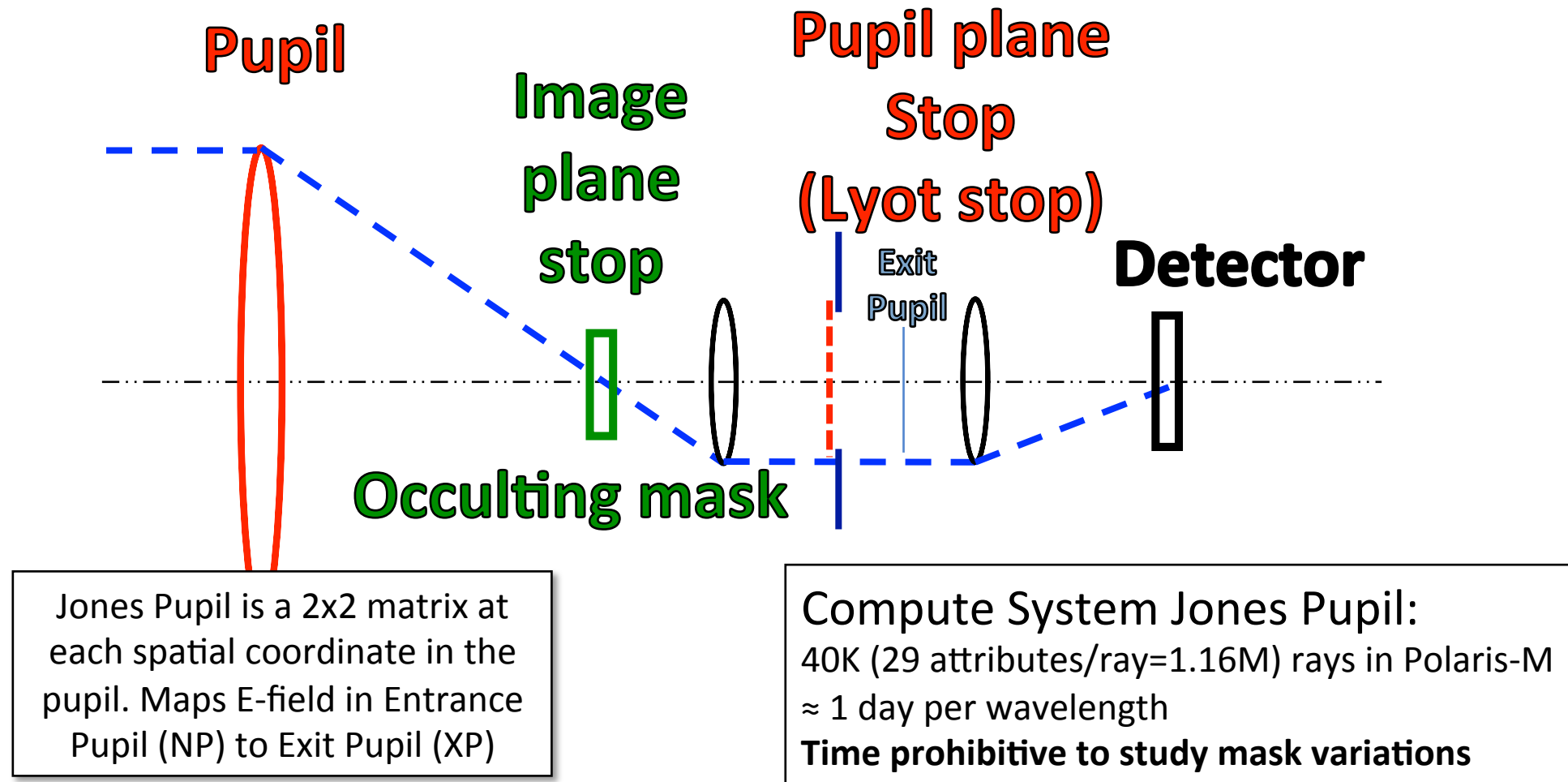
Presentation Outline

- Computational methods for using polarization ray tracing to study coronagraph designs with a Jones Pupil decomposition
- Measurements/modeling of form birefringence on primary mirror
 - Degrades contrast
- Future work:
 - Mitigation strategies in mask design
 - Sensitivity to mask fabrication errors

Assumptions in these Simulation Studies

- No deformable mirror optimization or EFC in HabEx prescription
- Measurements/modeling of form birefringence on primary mirror
 - Demonstration of capability to quantify degradation in contrast
- Novel method for measuring form birefringence on a large optic
- Test optic we measured is NOT HabEx mirror and given differences in coating technology our measurements are a worse case scenario (maybe 10x better is possible?)

Computing the HabEx Jones Pupil using Polaris-M

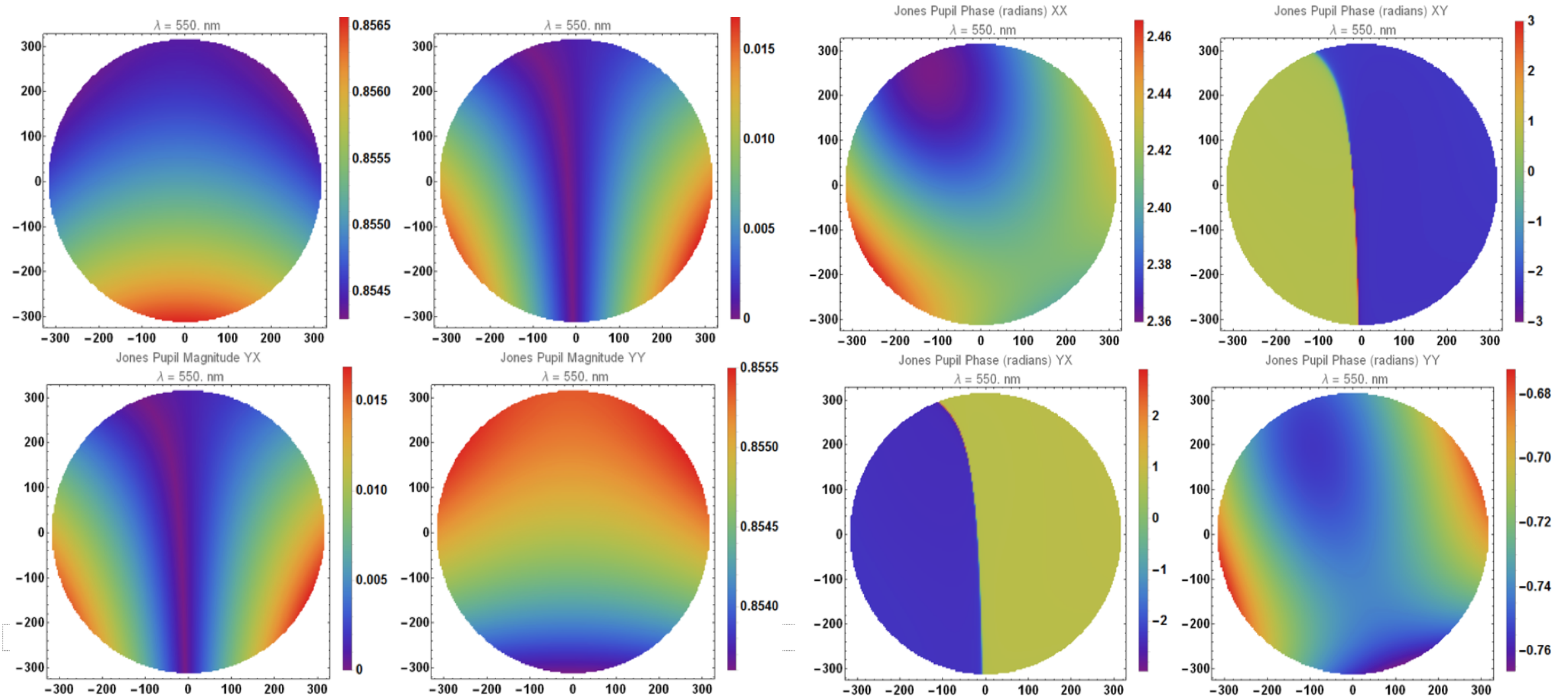


$$J(\xi, \chi) = \begin{pmatrix} J_{XX} & J_{XY} \\ J_{YX} & J_{YY} \end{pmatrix}$$

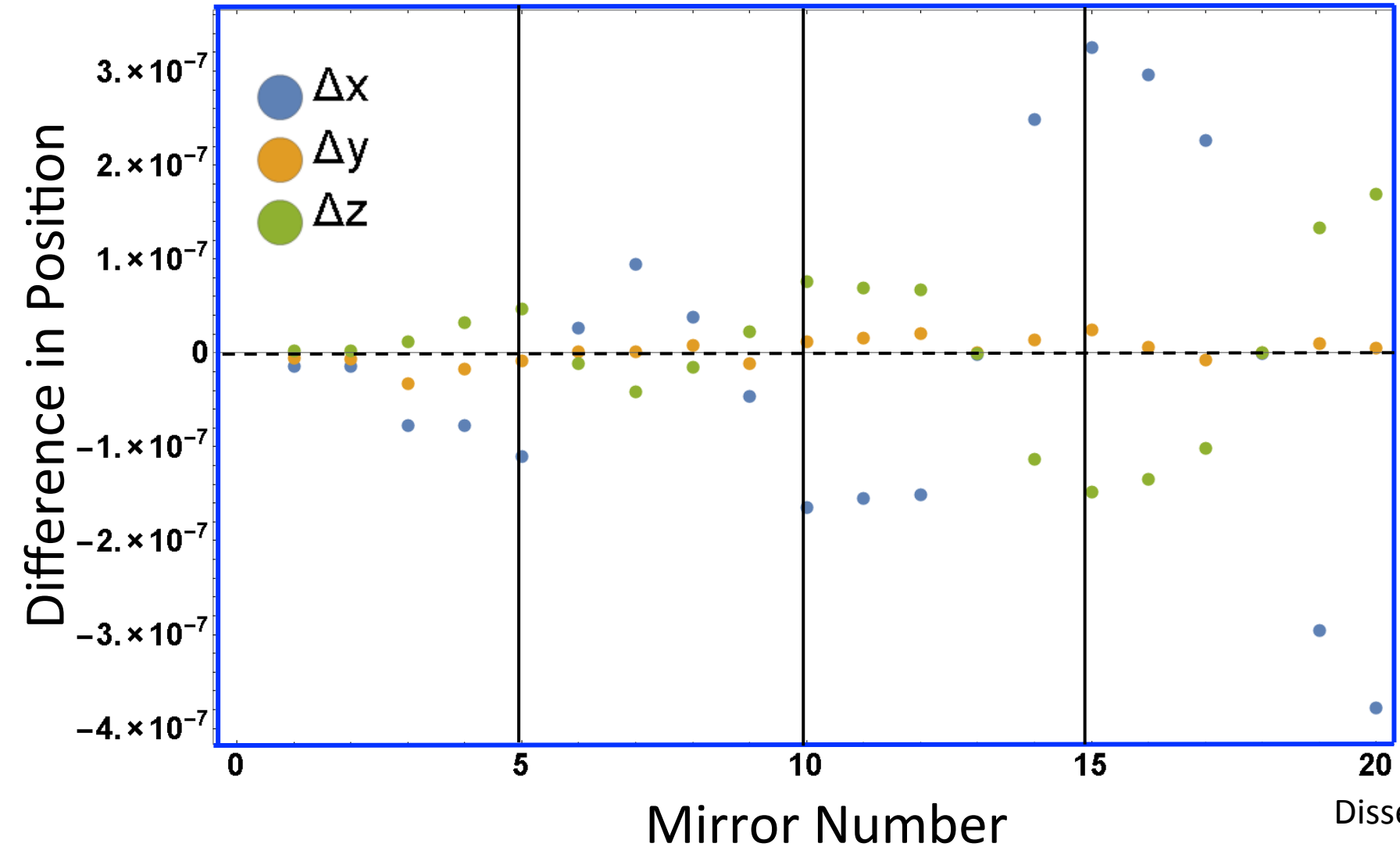
HabEx Jones Pupil from Polaris-M: detector plane @ 550 nm(no mask)

Amplitude

Phase [radians]



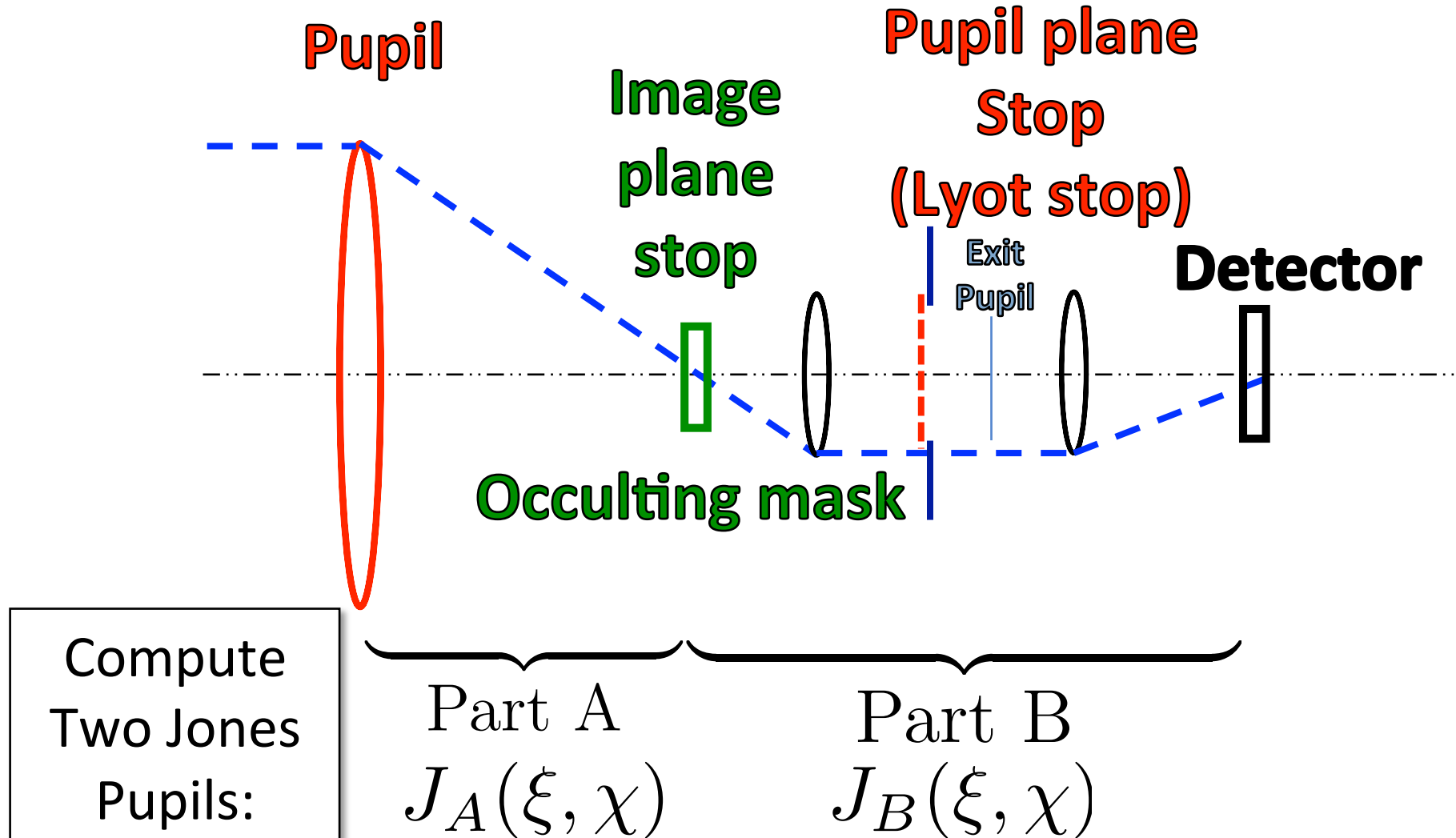
Code-V & Polaris-M Validation



k-vector residual
 $< 3 \times 10^{-7}$ mm
on mirror surfaces
for WFIRST-CGI

Computing the HabEx Jones Pupil with Mask

Pupil Decomposition Concept to Eliminate Redundancy



Implementing the HabEx Mask: *Pupil Decomposition Algebra*

No Mask:

$$J(\xi, \chi) = J_B(\xi, \chi) J_A(\xi, \chi)$$

2x2 matrix-
multiply

Insert Mask (**without redoing fore-optics & instrument ray trace!**):

$$J(\xi, \chi) = J_B(\xi, \chi) \mathcal{F}^{-1} \{ M \odot \mathcal{F} \{ J_A(\xi, \chi) \} \}$$

M : complex transmittance of the mask

Element-by-element
multiply

Analyze the behavior of the Jones Pupil, PSF, system contrast for various mask designs:

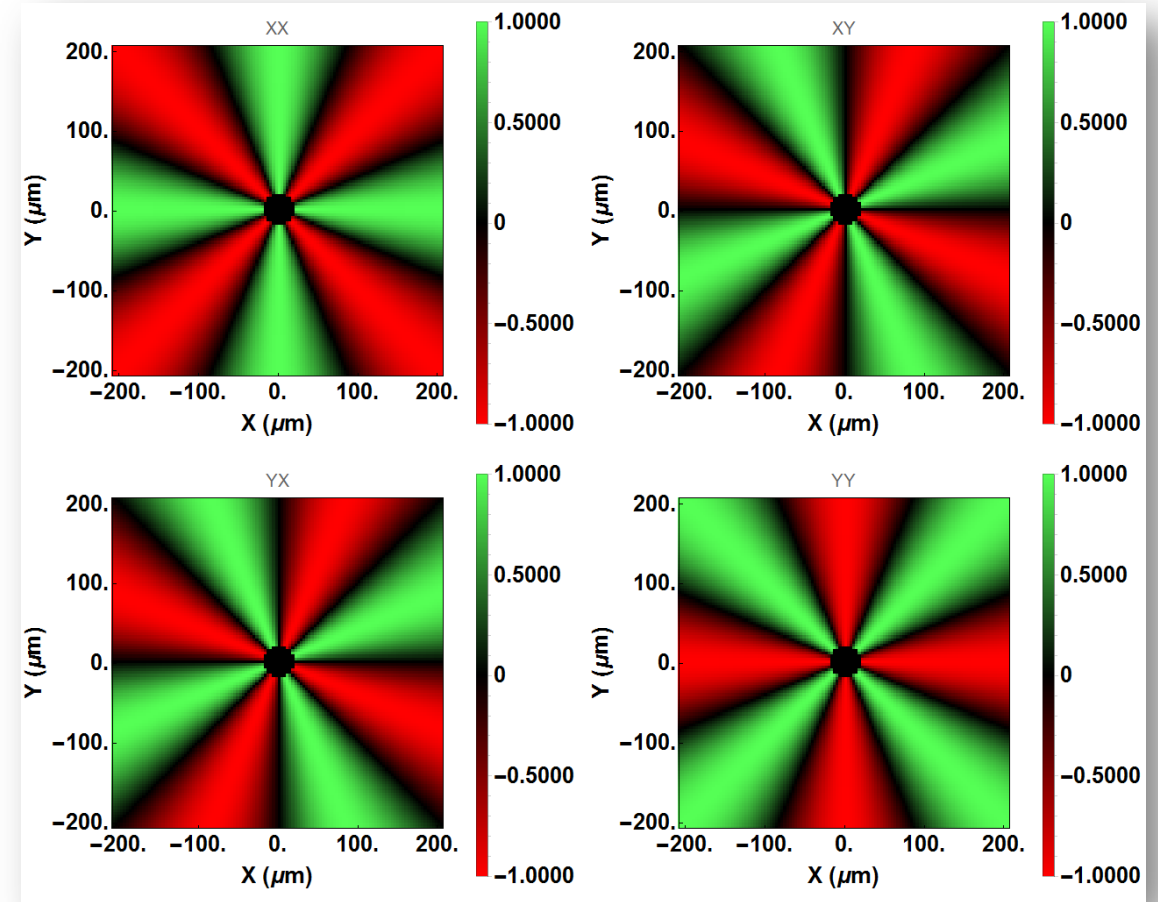
$$J(\xi, \chi; \mathbf{a}) = J_B(\xi, \chi) \mathcal{F}^{-1} \{ M(\mathbf{a}) \odot \mathcal{F} \{ J_A(\xi, \chi) \} \}$$

$\mathbf{a}$: mask attributes (e.g. size occulter, phase errors, fabrication tolerances)

Vector Vortex (VV) Transmittance

$$\begin{pmatrix} \cos(m \tan^{-1}(\frac{y}{x})) & \sin(m \tan^{-1}(\frac{y}{x})) \\ \sin(m \tan^{-1}(\frac{y}{x})) & -\cos(m \tan^{-1}(\frac{y}{x})) \end{pmatrix}$$

- Vector Vortex (charge, m=4)
- 40 micron diameter obscuration
- Future work:
 - Fabrication tolerances for liquid crystal VV



Presentation Outline

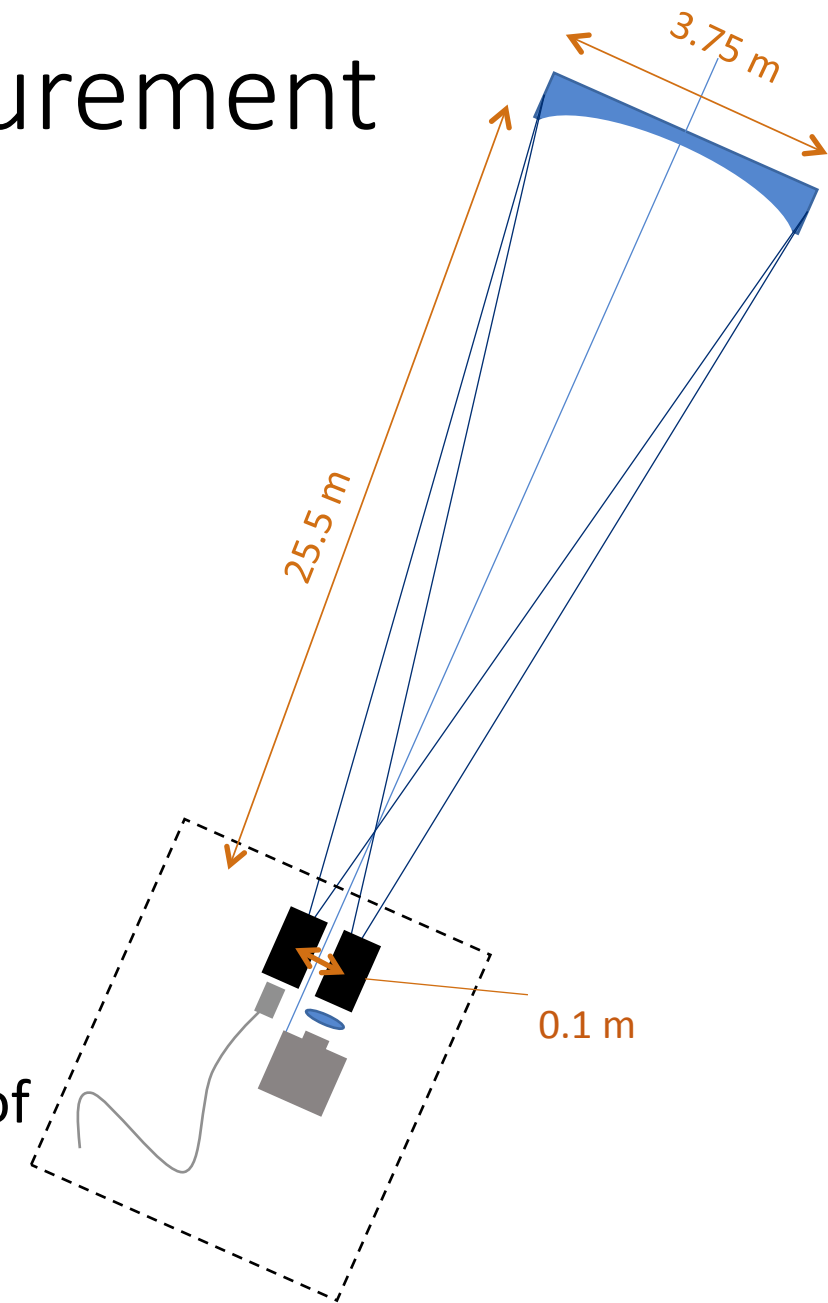
- Computational methods for using polarization ray tracing to study coronagraph designs with Jones Pupil decomposition
- **Measurements/modeling of form birefringence on primary mirror**
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Primary mirror form birefringence effects

- Took advantage of a unique opportunity to measure spatial changes in polarization reflectivity across a large (3.75-m) astronomical mirror
 - Al coated in a vacuum chamber at Kitt Peak
 - Bare Al natural oxide layer about 4nm
- Developed a precision instrument and software to measure birefringence and diattenuation across a 3.75-meter mirror
- Placed the measured results into our HabEx model & modeled the effect on the noise-equivalent contrast.

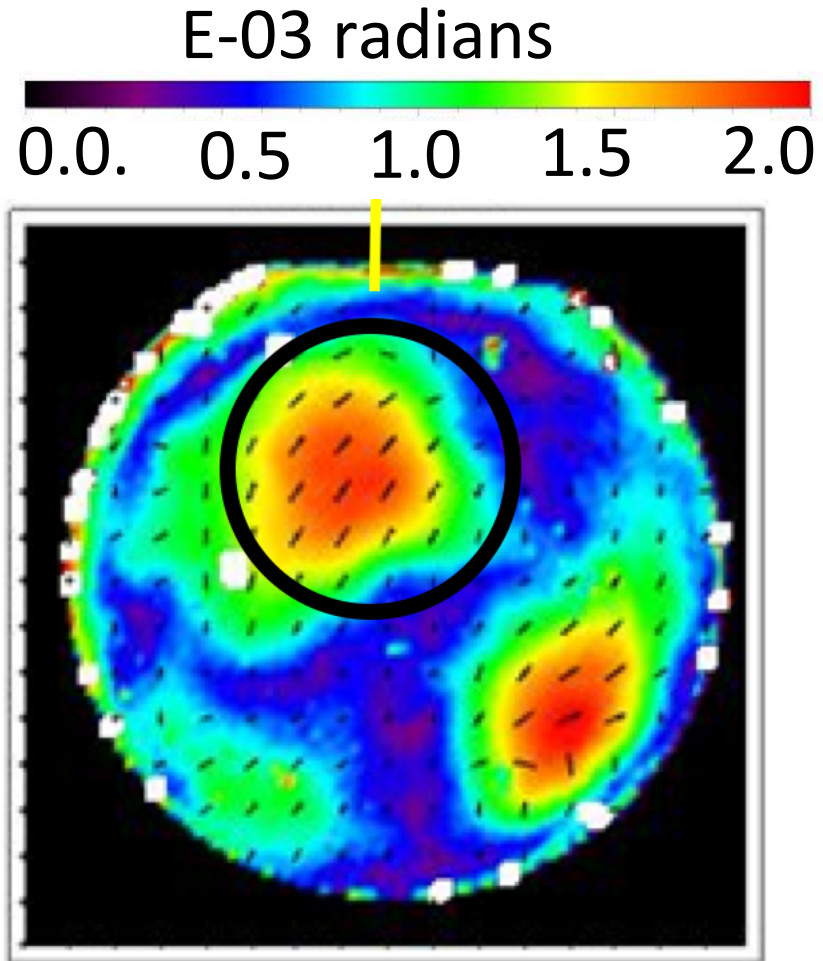
Form Birefringence Measurement

- Measurement concept
 - Identify polarization properties intrinsic to coating
 - Incident angles near 0° achieved by placing point source adjacent to center of curvature of mirror
 - With this geometry Fresnel equations predict
 - retardance $< 10^{-5}$
 - diattenuation $< 10^{-6}$
- System description
 - Source: Fiber coupled monochromator
 - Polarimetry: Two crossed Glan-Thompson polarizers mounted on motorized rotation stages
 - Detector: Scientific grade 16-bit camera
 - Mounting: 3-axis translation to align system with center of curvature. 2-tilt axis to aim source and camera at mirror.
 - Rotation about center axis to provide different system orientations

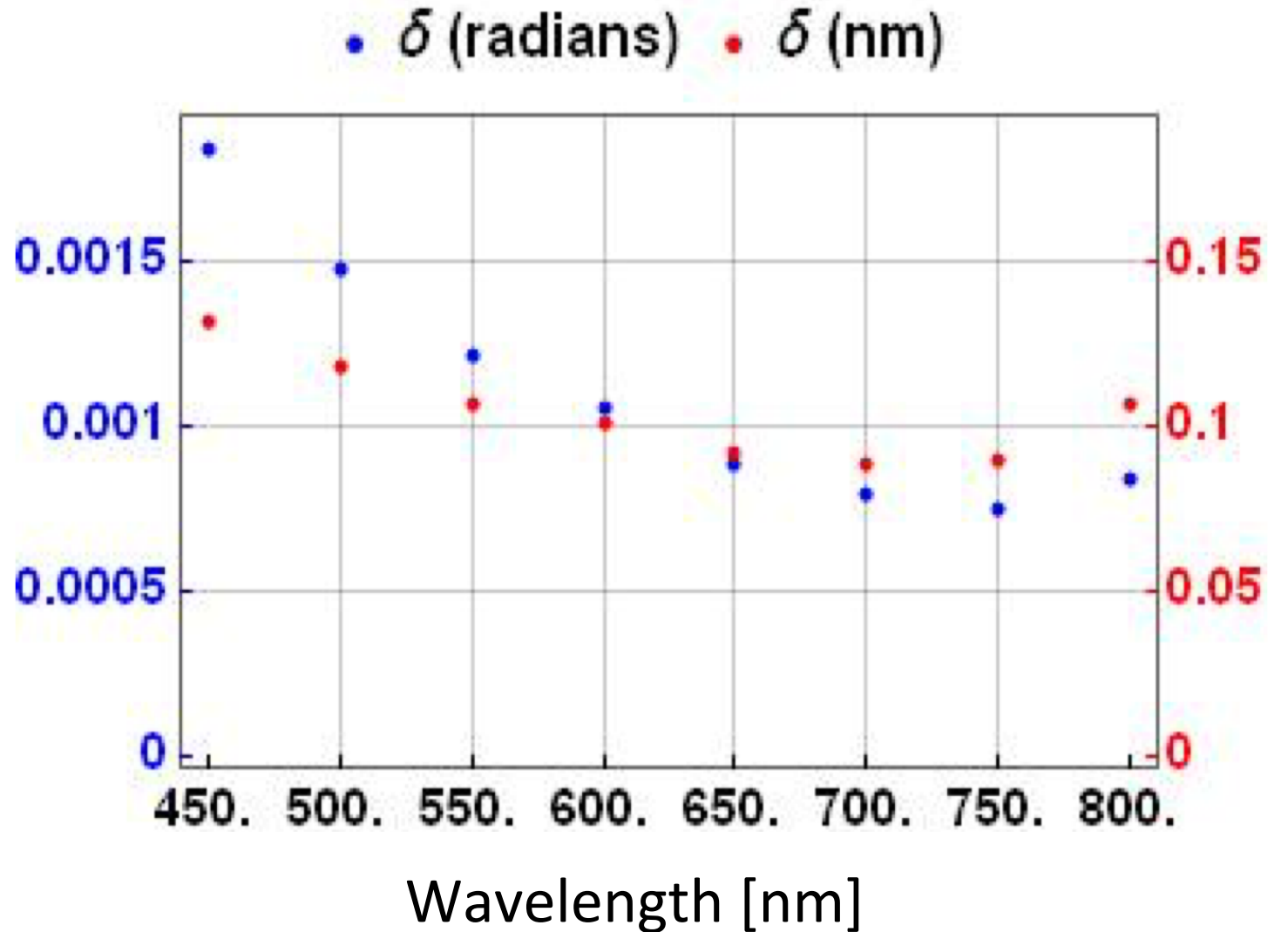


Dissertation work of Brian Daugherty

Form Birefringence Measurement



Dissertation work of Brian Daugherty



Noise Equivalent Contrast

Definition

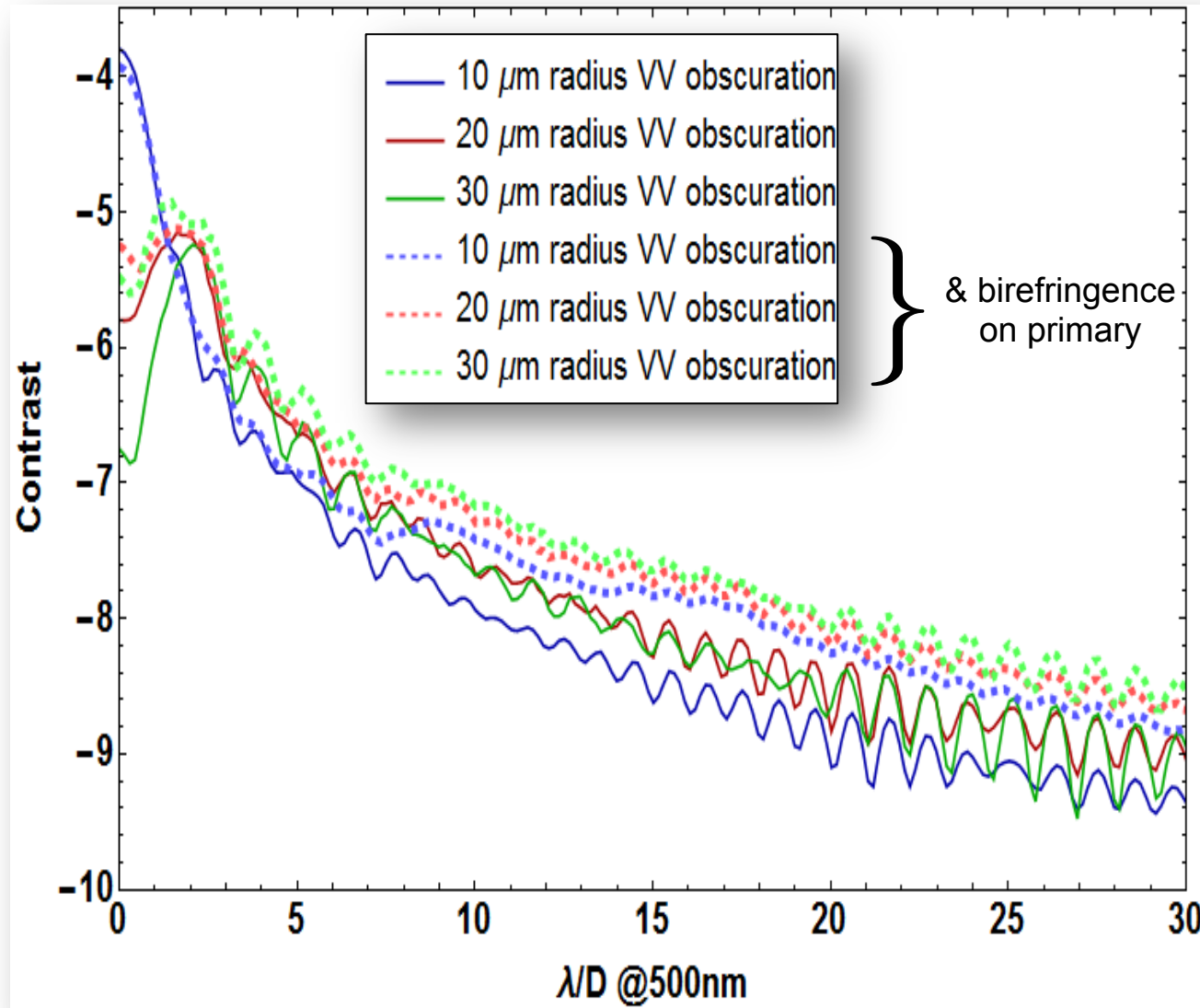
$$C_{\Delta(500)}^P(\mathbf{r}) = \log_{10} \left[\frac{1}{2} \left(\frac{\sum_{\lambda=450}^{\lambda=550} \langle I_{XX}(\mathbf{r}; \lambda) + I_{YY}(\mathbf{r}; \lambda) \rangle_{\mathbf{r}}}{\sum_{\lambda=450}^{\lambda=550} I_{XX}^{NoMask}(0; \lambda) + I_{YY}^{NoMask}(0; \lambda)} \right) \right]$$

where

$$PSF(x, y) = \begin{pmatrix} I_{XX}(x, y) & I_{XY}(x, y) \\ I_{YX}(x, y) & I_{YY}(x, y) \end{pmatrix}$$

- Sum the on-diagonal polarimetric elements
- Numerator is poly-chromatic PSF with occulting mask
- Denominator unmasked PSF at origin

HabEx 1709; Contrast [450, 475, 503, 525, 550 nm]
with and without birefringence on primary mirror

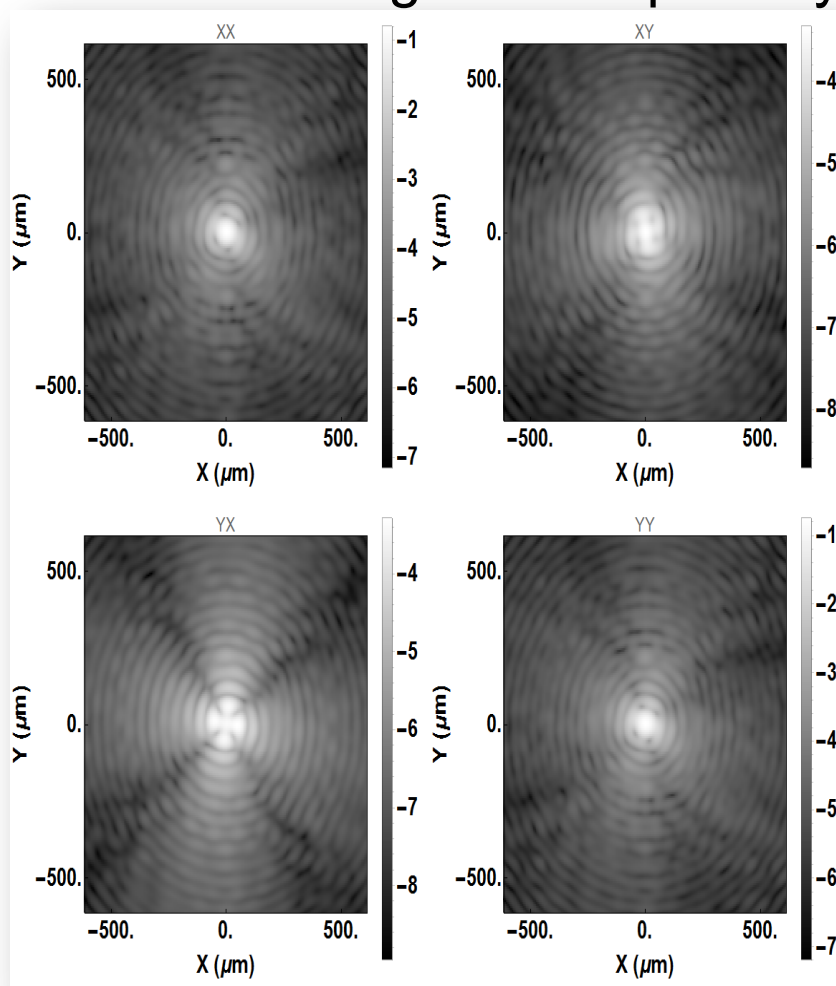


Approximately 5x
degradation in contrast
when including form
birefringence on primary
mirror

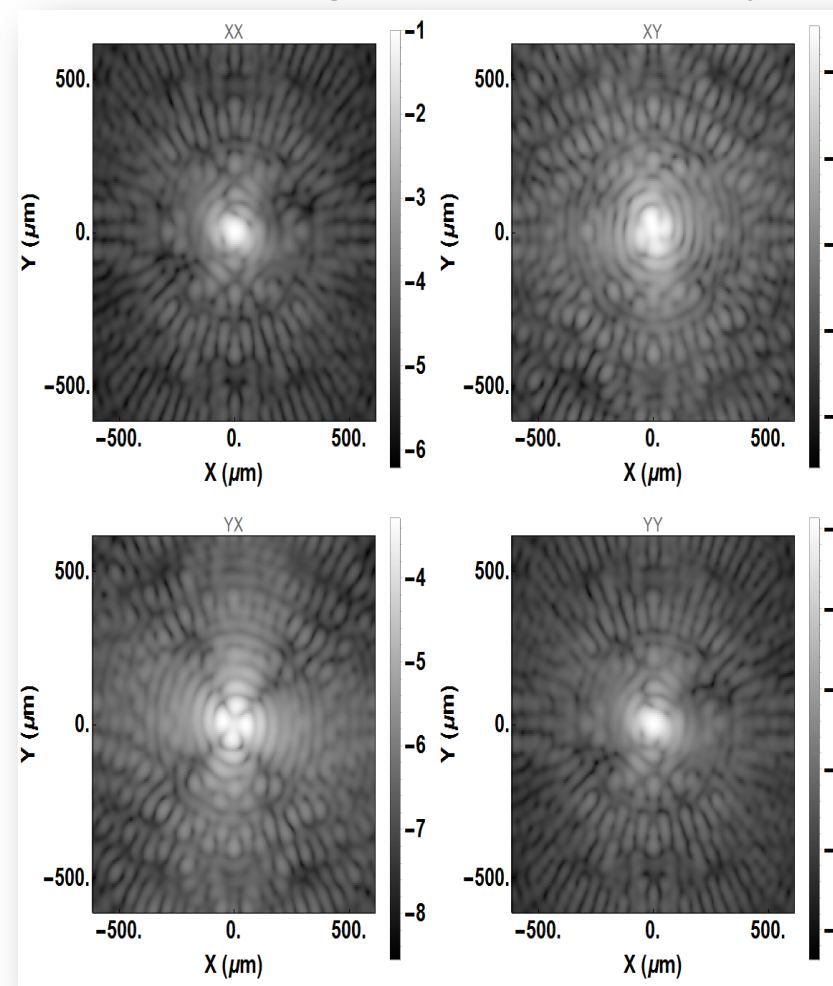
Dissertation work of Jeff Davis

HabEx 1709; **Log10 PSF** [450=>550 nm]
VV4 (obscuration radius 10 microns)

No Birefringence on primary

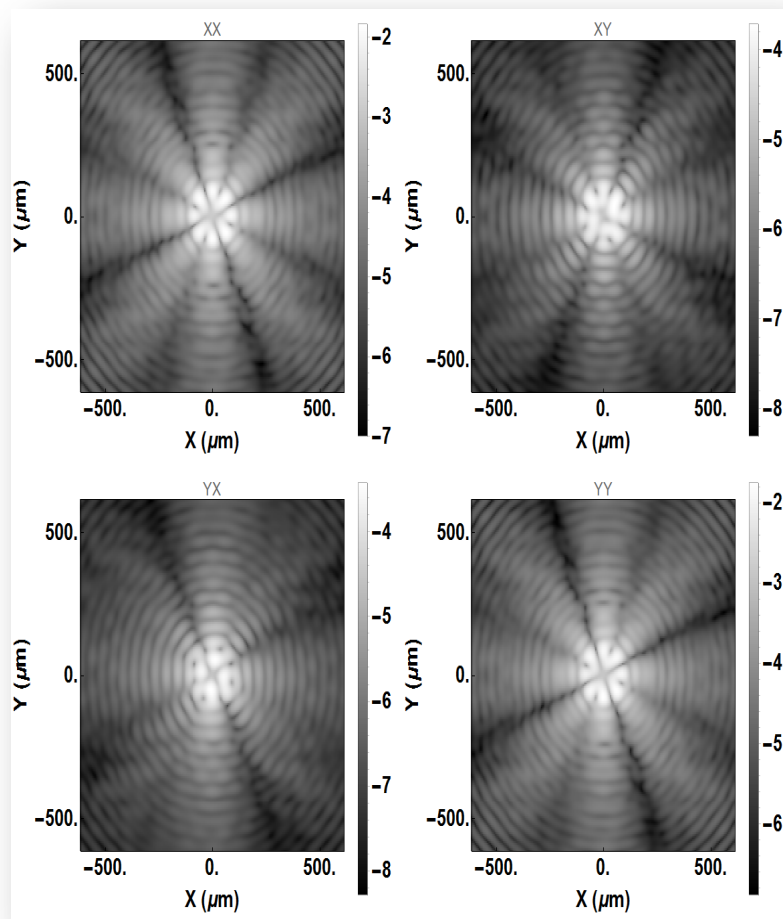


Birefringence on primary

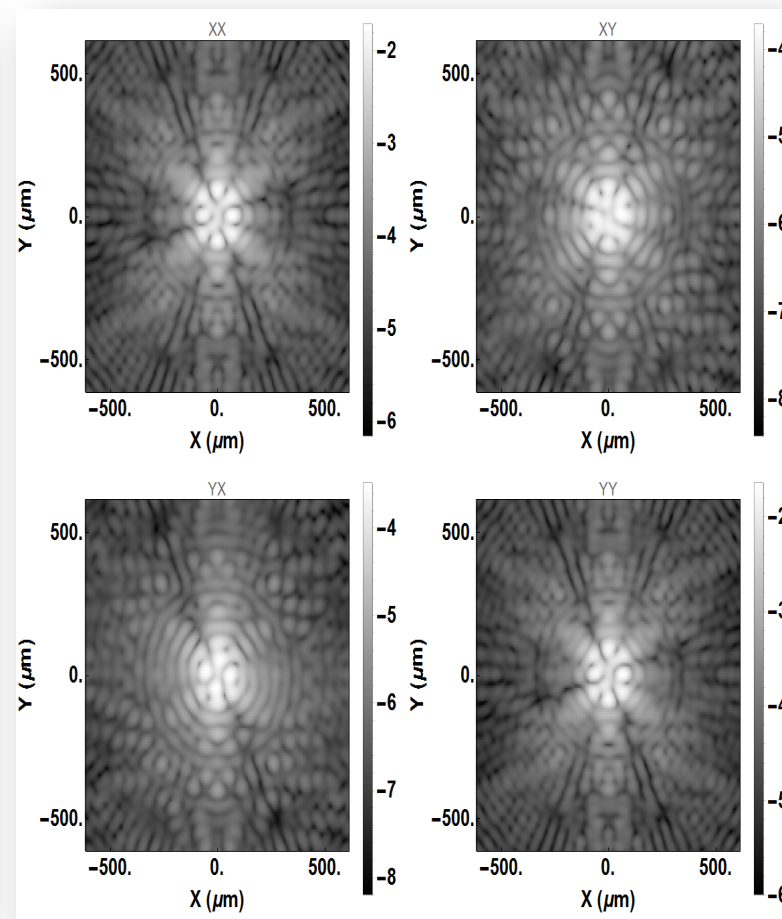


HabEx 1709; **Log10 PSF** [450=>550 nm] VV4 (obscuration radius 20 microns)

No Birefringence on primary

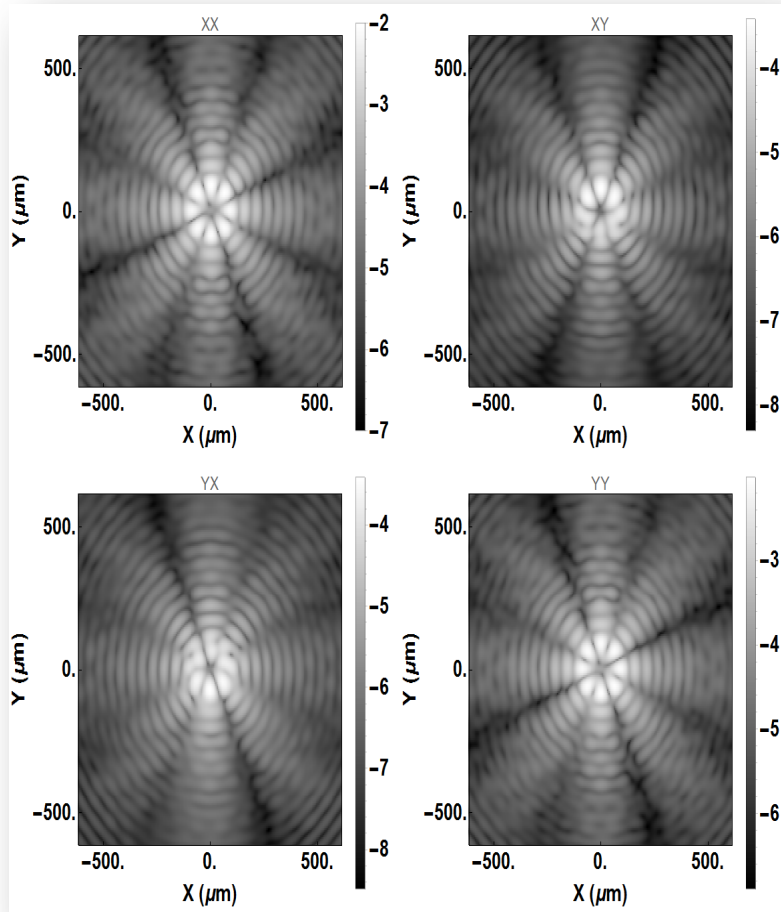


Birefringence on primary

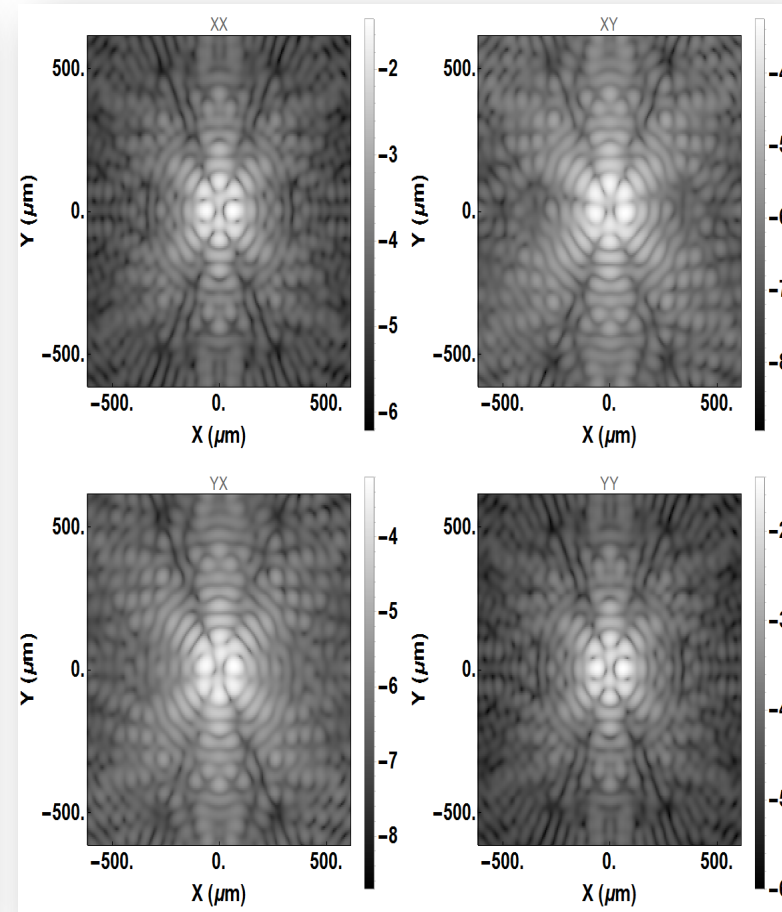


HabEx 1709; **Log10 PSF** [450=>550 nm]
VV4 (obscuration radius 30 microns)

No Birefringence on primary



Birefringence on primary



Conclusions

- Polarization ray tracing can be made computational feasible for studying mask designs and polarization properties of large optics with Jones Pupil decomposition
- Polarization and form birefringence degrades contrast
- Future work:
 - Are mitigation strategies in mask design possible?
 - Sensitivity to mask fabrication errors
 - Treat polarization properties of surfaces as random processed

Future Work

Optimize Linear System between E-field at entrance pupil (NP) and exit pupils (XP):

$$E_{XP} = J(\xi, \chi; \mathbf{a}) E_{NP}$$

- Create Scene Models (spectra-polarimetric) for E_{NP} under 2 hypotheses, eg: exoplanet present, exoplanet habitable, atmospheric dust/disk types
- Optimize mask attributes for discriminating these 2 hypotheses from E_{XP}
- Expertise in this type of optimization problem for scientific imaging:
 - Use Kullback-Leibler divergence between $\text{pr}(E_{XP} | 1)$ and $\text{pr}(E_{XP} | 2)$ as merit function
 - Closed-form gradient wrt mask attributes for normal $\text{pr}(E_{XP} | 1)$ and $\text{pr}(E_{XP} | 2)$